

February 09, 2026

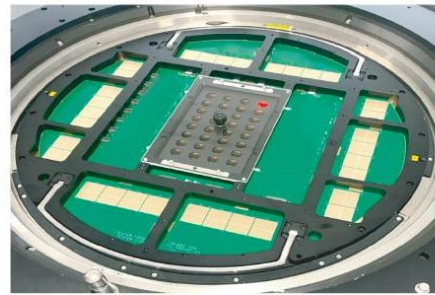
Nidec Advance Technology to Exhibit Products at SEMICON Korea 2026

Nidec Advance Technology Corporation (“Nidec Advance Technology” or the “Company”) today announced that it will exhibit products at SEMICON Korea 2026, which will be held at COEX Convention Center in Seoul, South Korea, from Wednesday, February 11 – Friday, February 13, 2026.

This upcoming exhibition will witness the Company showcase, among others, its NATS series (inspection equipment to support next-generation power semiconductors (IGBT/SiC)) and state-of-the-art inspection solutions developed by the Nidec Group’s comprehensive technology.



NTAS-1304



2D MEMS probe card

Nidec SV Probe Corporation, a subsidiary of Nidec Advance Technology, will display, as cutting-edge solutions for the probe card (wafer inspection jig): the TC (thermocouple) probe, which can measure semiconductors’ temperatures (to be exhibited for the first time in South Korea); a probe card based on the 2D MEMS technology; and the latest model of the GATS series (the semiconductor package substrate electrical testing system which will be the Company’s flagship product).

About SEMICON Korea 2026:

- Period: Wednesday, February 11 – Friday, February 13, 2026
- Venue: COEX Convention Center in Seoul
- Booth: G004, Hall Grand Ballroom, F1
- Official website: <https://www.semiconkorea.org/en>

Nidec Advance Technology’s exhibition and panel presentations will include:

- 2D-MEMS probe card
- Probe to measure devices’ temperature
- NATS-1000/1700 series (insulation/static/dynamic characteristics inspection equipment for IGBT/SiC modules)
- NATS-1300 series (KGD testing equipment)
- R-700 series (AC/DC multi tester)
- Pin probe for ultra-high-precision inspections
- Vertical high-current probe
- Glass micro-hole machining
- RWi-300MK (wafer AOI)
- GATS-8360 (AI server large substrate electrical testing system)

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